## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No
Filing Date March 17, 2004
Inventor
Assignee Micron Technology, Inc.
Group Art Unit
Examiner R. Kobert
Attorney's Docket No
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. No admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 2-28-05

D. Brent Kenady Reg. No. 40,045

Customer No. 021567

Sheet 1 of 1

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